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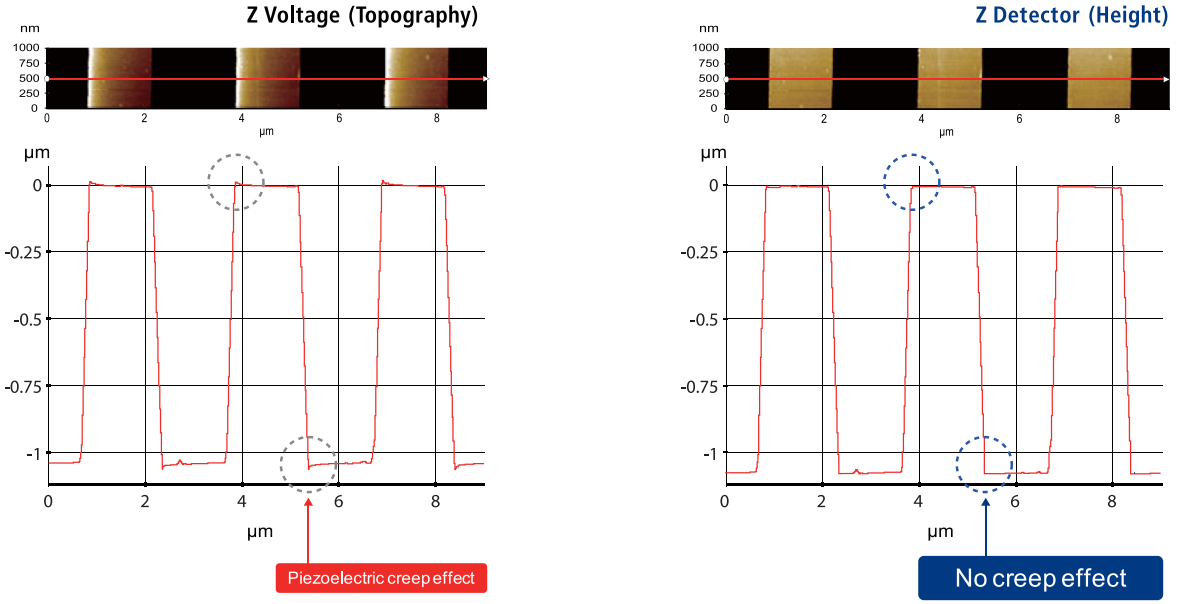

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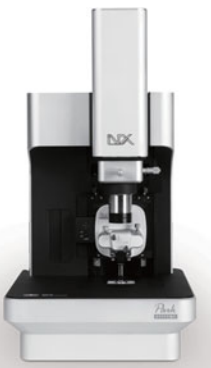

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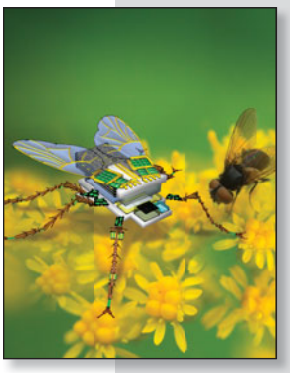

ON THE COVER

Thin-film piezoelectric MEMS. This issue of *MRS Bulletin* focuses on some of the challenges microelectromechanical systems (MEMS) face as they move to smaller sizes and increased integration density, while requiring fast response and large motions. Advances in the field are being driven by and are prompting advances in heterostructure design and theoretical investigations. On the cover is a notional millimeter-scale robotic system based on PZT MEMS and highly integrated microelectronics. Green regions indicate PZT MEMS actuators, and the stacked "chips" on the body segments represent other required microelectronic subsystems. The robot is a hexapod (six-legged)-based flight-capable design. See the technical theme that begins on page 1007.

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EDITORIAL OFFICE 506 Keystone Drive, Warrendale, PA 15086-7573 USA
Bulletin@mrs.org tel 724.779.2747 fax 724.779.8313 www.mrs.org

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The Materials Research Society (MRS), a not-for-profit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes almost 16,000 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and over 80 countries.

The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors three major international annual meetings encompassing approximately 125 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is a member of the Alliance for Science & Technology Research in America and is an affiliate of the American Institute of Physics.

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MRS Bulletin (ISSN: 0883-7694, print; ISSN 1938-1425, online) is published 12 times a year by the Materials Research Society, 506 Keystone Drive, Warrendale, PA 15086-7573. Periodical postage paid at New York, NY, and at additional mailing offices. POSTMASTER: Send address changes to *MRS Bulletin* in care of the Journals Department, Cambridge University Press, 100 Brook Hill Drive, West Nyack, NY 10994-2113, USA. Printed in the U.S.A.

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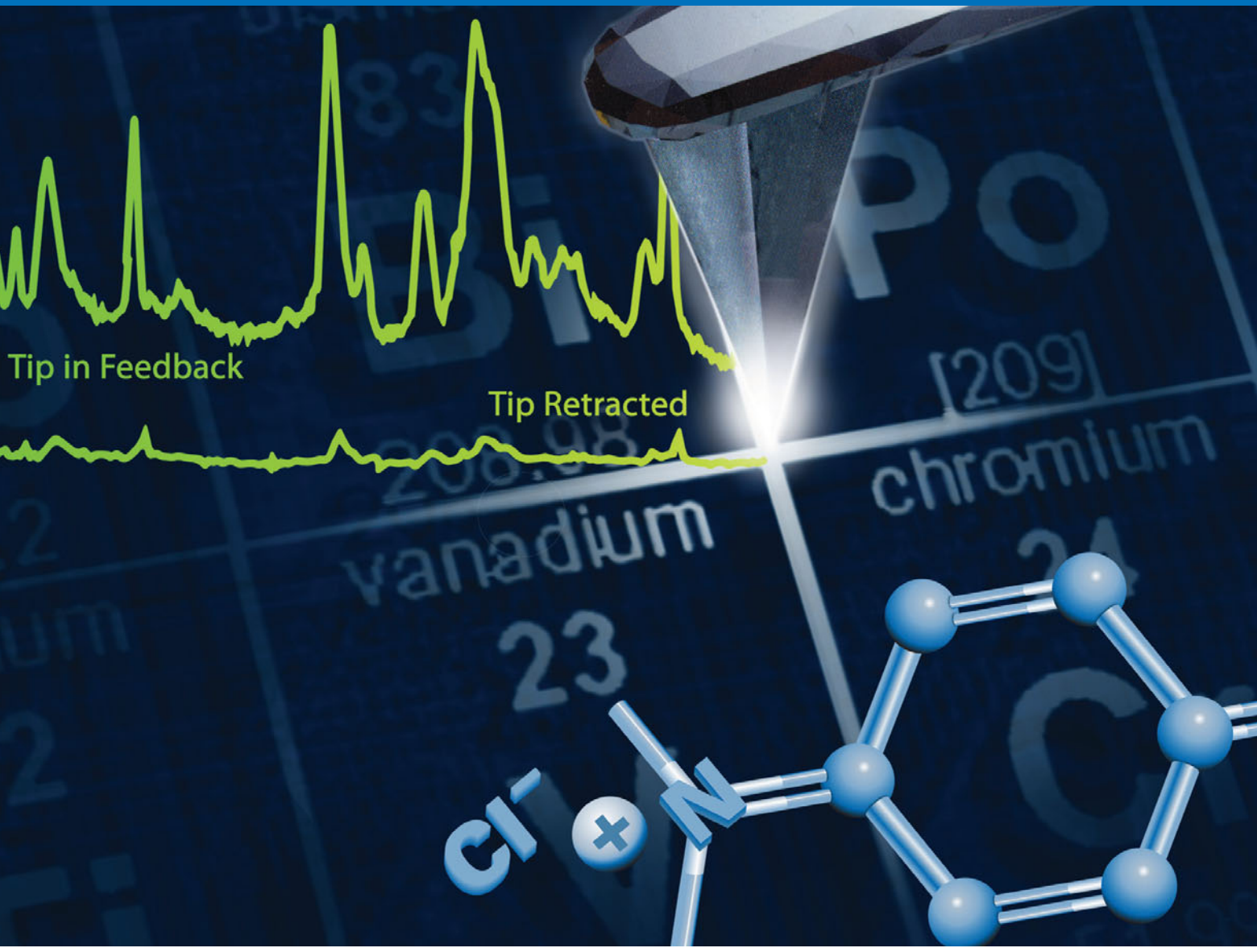

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